Advanced Small Signal MOSFET 2N7000BU/2N7000TA

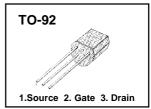
FEATURES

- Fast Switching Times
- Improved Inductive Ruggedness
- Lower Input Capacitance
- Extended Safe Operating Area
- Improved High Temperature Reliability

 $BV_{DSS} = 60 V$

 $R_{DS(on)} = 5.0 \Omega$

 $I_D = 200 \text{ mA}$



Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage	60	V
	Continuous Drain Current (T _C =25 °C)	200	mA
I _D	Continuous Drain Current (T _C =100°C)	110	IIIA
I _{DM}	Drain Current-Pulsed ①	1000	mA
V_{GS}	Gate-to-Source Voltage	±30	V
5	Total Power Dissipation (T _C =25℃)	400	mW
P_{D}	Linear Derating Factor	3.2	mW/℃
101	Operating Junction and	55.4.450	12
T_J , T_STG	Storage Temperature Range	- 55 to +150	°C
L	Maximum Lead Temp. for Soldering	1	
TL	Purposes, 1/8? from case for 5-seconds	300	

Thermal Resistance

Symbol	Characteristic	Тур.	Max.	Units
$R_{\Theta JA}$	Junction-to-Ambient		312.5	сw



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Electrical Characteristics (T_C =25 $^{\circ}$ C unless otherwise specified)

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition	
BV _{DSS}	Drain-Source Breakdown Voltage	60	1		V	V _{GS} =0V,I _D =250μA	
	Gate Threshold Voltage	0.3		3.9	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
$V_{GS(th)}$		0.4		2.2		$V_{DS} = V_{GS}, I_{D} = 1 \text{mA}$	
	Gate-Source Leakage, Forward			100	nA	V _{GS} =15V	
I _{GSS}	Gate-Source Leakage, Reverse			-100	IIA	V _{GS} =-15V	
	Drain-to-Source Leakage Current			250		V _{DS} =60V	
I _{DSS}				1000	μA	V_{DS} =45 V , T_{C} =125 $^{\circ}$ C	
_	Static Drain-Source					V 40VI 0.5A	
R _{DS(on)}	On-State Resistance ②			5.0	Ω	$V_{GS}=10V,I_{D}=0.5A$	
g _{fs}	Forward Transconductance ②	0.1	0.3		S	V _{DS} =15V,I _D =0.5A	
C _{iss}	Input Capacitance		30			V 0VV 25V	
C _{oss}	Output Capacitance		12		pF	V_{GS} =0V, V_{DS} =25V, f =1MHz	
C _{rss}	Reverse Transfer Capacitance		3.0				
t _{d(on)}	Turn-On Delay Time			10			
t _r	Rise Time			10	ns	V_{DD} =30V, I_{D} =0.5A, R_{G} =15 Ω 23	
t _{d(off)}	Turn-Off Delay Time			10			
t _f	Fall Time			10			

Notes

- ① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- ② Pulse Test : Pulse Width = 250µs, Duty Cycle ≤ 2%
- 3 Essentially Independent of Operating Temperature



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